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- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

```
(stereo <near/5> imag*)
<paragraph> (((estimat* or
project* or predict* or
interpolat*) <near/4> (imag*
```


Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

 Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)
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- 3) Select search operators when using multiple keywords.
- 4) Limit the results by selecting Search Options.
- 5) Click Search. See [Search Examples](#)

ono In: Author

And

stereo In: All Fields

And

In: All Fields

Search Clear

Note: This function returns plural and suffixed forms of the keyword(s).

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